

ON Semiconductor®

FDMA3028N

Dual N-Channel PowerTrench® MOSFET 30 V, 3.8 A, 68 m Ω

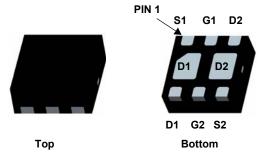
Features

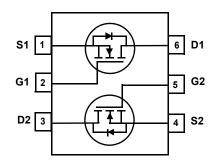
- Max. $R_{DS(on)}$ = 68 m Ω at V_{GS} = 4.5 V, I_D = 3.8 A
- Max. $R_{DS(on)}$ = 88 m Ω at V_{GS} = 2.5 V, I_D = 3.4 A
- Max. $R_{DS(on)}$ = 123 m Ω at V_{GS} = 1.8 V, I_D = 2.9 A
- Low profile 0. 8 mm maximum in the new package MicroFET 2x2 mm
- RoHS Compliant

General Description

This device is designed specifically as a single package solution for dual switching requirements in cellular handset and other ultra-portable applications. It features two independent N-Channel MOSFETs with low on-state resistance for minimum conduction losses. The MicroFET 2x2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.







MicroFET 2x2

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		30	V
V _{GS}	Gate to Source Voltage		±12	V
I _D	Drain Current -Continuous	(Note 1a)	3.8	۸
	-Pulsed		16	Α
P_{D}	Power Dissipation	(Note 1a)	1.5	14/
	Power Dissipation	(Note 1b)	0.7	W
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

		Thermal Resistance for Single Operation, Junction to Ambient	(Note 1a)	86	
		Thermal Resistance for Single Operation, Junction to Ambient	(Note 1b)	173	
_		Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1c)	69	°C/\\
$R_{\theta JA}$	ЭJA	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1d)	151	°C/W
		Thermal Resistance for Single Operation, Junction to Ambient	(Note 1e)	160	
		Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1f)	133	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
328	FDMA3028N	MicroFET 2X2	7 "	8 mm	3000 units

Electrical Characteristics $T_J = 25 \, ^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0 V	30			V
$\Delta BV_{DSS} \over \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		23		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±12 V, V _{DS} = 0 V			±100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	0.6	0.9	1.5	V
$\Delta V_{GS(th)} = \Delta T_J$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25 °C		-3		mV/°C
		$V_{GS} = 4.5 \text{ V}, I_D = 3.8 \text{ A}$		46	68	
_	Static Drain to Source On Resistance	$V_{GS} = 2.5 \text{ V}, I_D = 3.4 \text{ A}$		56	88	mΩ
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 1.8 \text{ V}, I_D = 2.9 \text{ A}$		80	123	11122
		V_{GS} = 4.5 V, I_D = 3.8 A, T_J = 125 °C		72	108	
g _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 3.8 \text{ A}$		15		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V - 45 V V - 0 V	282	375	pF
Coss	Output Capacitance	V _{DS} = 15 V, V _{GS} = 0 V, — f = 1 MHz	40	55	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12	29	45	pF
R_g	Gate Resistance		2.4		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay		5.3	11	ns
t _r	Rise Time	V _{DD} = 15 V, I _D = 3.8 A,	3	10	ns
t _{d(off)}	Turn-Off Delay	V_{DD} = 15 V, I_{D} = 3.8 A, V_{GS} = 4.5 V, R_{GEN} = 6 Ω	15	27	ns
t _f	Fall Time		2.5	10	ns
$Q_{g(TOT)}$	Total Gate Charge	V 45.V.I. 0.0.A	3.7	5.2	nC
Q_{gs}	Gate to Source Charge	V_{DD} = 15 V, I_{D} = 3.8 A V_{GS} = 5 V	0.4		nC
Q _{gd}	Gate to Drain "Miller" Charge	VGS - 3 V	1		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.3 \text{ A}$	(Note 2)	0.7	1.2	V
t _{rr}	Reverse Recovery Time	I _F = 3.8 A, di/dt = 100 A/μs		12	22	ns
Q _{rr}	Reverse Recovery Charge			3.3	10	nC

Electrical Characteristics T_J = 25 °C unless otherwise noted

Notes:

- 1. R_{0JA} is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.

 (a) $R_{\theta JA} = 86 \text{ °C/W}$ when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB. For single operation.

 - (b) $R_{\theta JA}$ = 173 °C/W when mounted on a minimum pad of 2 oz copper. For single operation.
 - (c) $R_{\theta JA}$ = 69 °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB. For dual operation.
 - (d) $R_{\theta JA}$ = 151 o C/W when mounted on a minimum pad of 2 oz copper. For dual operation.
 - (e) $R_{\theta JA}$ = 160 °C/W when mounted on a 30mm² pad of 2 oz copper. For single operation.
 - (f) $\rm\,R_{\rm \theta JA}$ = 133 $^{\rm o} \rm{C/W}$ when mounted on a 30mm² pad of 2 oz copper. For dual operation.



a. 86 °C/W when mounted on a 1 in² pad of 2 oz copper



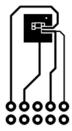
b. 173 °C/W when mounted on a minimum pad of 2 oz copper



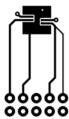
c. 69 °C/W when mounted on a 1 in2 pad of 2 oz copper



d. 151 °C/W when mounted on a minimum pad of 2 oz copper



e. 160 °C/W when mounted on 30mm² pad of 2 oz copper



f. 133 °C/W when mounted on 30mm² of 2 oz copper

2. Pulse Test: Pulse Width < 300 us, Duty Cycle < 2.0%

Typical Characteristics T_J = 25°C unless otherwise noted

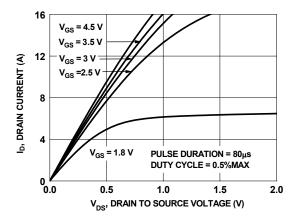


Figure 1. On Region Characteristics

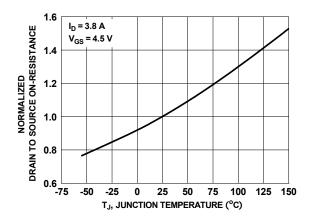


Figure 3. Normalized On Resistance vs. Junction Temperature

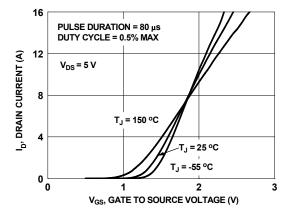


Figure 5. Transfer Characteristics

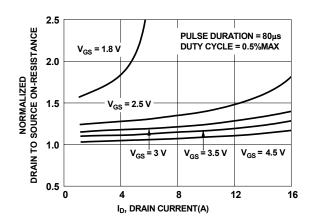


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

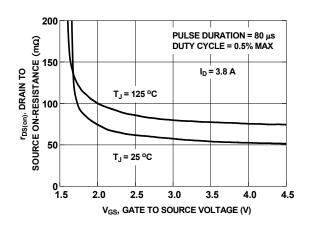


Figure 4. On-Resistance vs Gate to Source Voltage

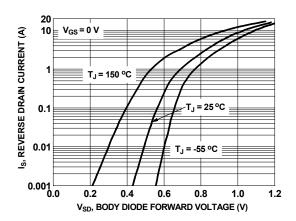


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

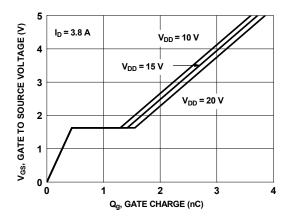


Figure 7. Gate Charge Characteristics

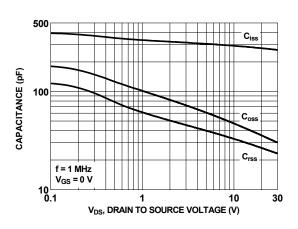


Figure 8. Capacitance vs. Drain to Source Voltage

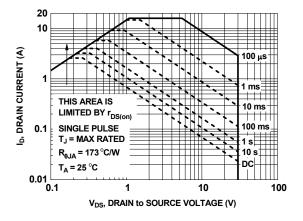


Figure 9. Forward Bias Safe Operating Area

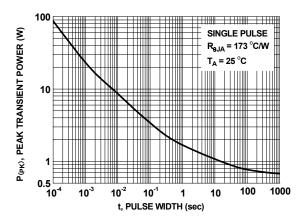


Figure 10. Single-Pulse Maximum Power Dissipation

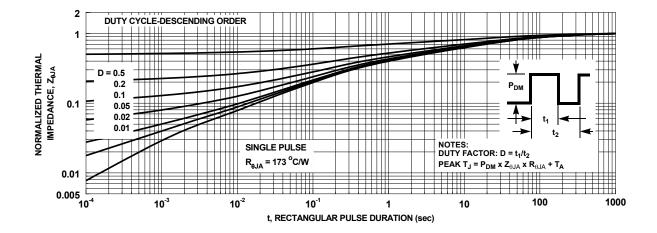
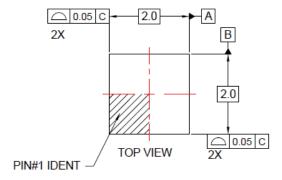
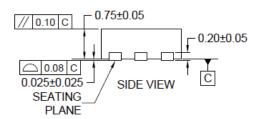
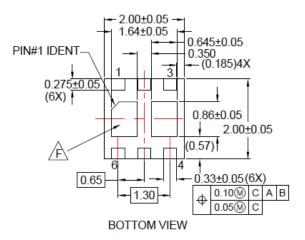


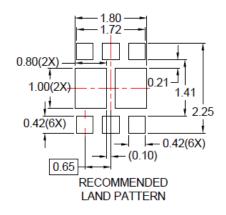
Figure 11. Junction-to-Ambient Transient Thermal Response Curve

Dimensional Outline and Pad Layout









NOTES:

- A. CONFORM TO JADEC REGISTRATIONS MO-229, VARIATION VCCC, EXCEPT WHERE NOTED.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.
- E. DRAWING FILENAME: MKT-UMLP16Erev4
- F. NON-JEDEC DUAL DAP

Package drawings are provided as a service to customers considering ON Semiconductor components. Drawings may change in any manner without notice. Please note the revision and/or date on the drawing and contact a ON Semiconductor representative to verify or obtain the most recent revision. Package specifications do not expand the terms of ON Semiconductor worldwide terms and conditions, specif-ically the warranty therein, which covers ON Semiconductor products.

ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hol

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Phone: 421 33 790 2910

Japan Customer Focus Center
Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative